# 2, 4, and 8-Channel **Low-Capacitance ESD Protection Array**

# **Product Description**

The CM1230 is a family of 2, 4 and 8 channel, very low capacitance ESD protection diode arrays in a CSP form factor. It is ideal for protecting systems with high data and clock rates or for circuits that need low capacitive loading. Each channel consists of a pair of ESD diodes that act as clamp diodes to steer ESD current pulses to either the positive or negative supply rail. A Zener diode is integrated between the positive and negative supply rails. The V<sub>CC</sub> rail is protected from ESD strikes and eliminates the need for a bypass capacitor to absorb positive ESD strikes to ground. Each channel can safely dissipate ESD strikes of ±8 kV, meeting the Level 4 requirement of the IEC61000-4-2 international standard as well as ±15 kV air discharges per the IEC61000-4-2 specification. Using the MIL-STD-883 (Method 3015) specification for Human Body Model (HBM) ESD, the pins are protected for contact discharges at greater than ±15 kV.

This device is well-suited for next generation wireless handsets that implement high-speed serial interface solutions for the LCD display and camera interfaces. In these designs, a tolerance above 1.5 pF cannot be tolerated when high data rates are transferred between the baseband choppiest and the LCD driver/controller Is. Higher capacitive loading normally causes the rise and fall times to slow which hampers the functionality of circuit and operation of the wireless handset. The CM1230 incorporates OptiGuard™ which results in improved reliability at assembly. The CM1230 is available in a space-saving, low profile Chip Scale Package with RoHS-compliant, lead-free finishing.

#### **Features**

- Two, Four, and Eight Channels of ESD Protection
- Provides ESD Protection to IEC61000-4-2 Level 4 ±8 kV Contact Discharge & ±15 kV Air Discharge
- Low Loading Capacitance of 0.8 pF Typical
- Minimal Capacitance Change with Temperature and Voltage
- Channel I/O to GND Capacitance Difference of 0.02 pF Typical is Ideal for Differential Signals
- Channel I/O to I/O Capacitance 0.15 pF Typical
- Zener Diode Protects Supply Rail and Eliminates the Need for External By-pass Capacitors
- Each I/O Pin Can Withstand Over 1000 ESD Strikes\*
- Available in 4, 6 and 10 Bump Chip Scale Packages (CSP)
- OptiGuard™ Coated for Improved Reliability at Assembly
- These Devices are Pb-Free and are RoHS Compliant

# **Applications**

- I/O Port Protection for Mobile Handsets, Notebook Computers, DSCs, MP3 Players, PDAs, etc. Including USB, 1394 and Serial ATA
- LCD and Camera Data Lines in Wireless Handsets that use High-speed Serial Interfaces
- Wireless Handsets



# ON Semiconductor®

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**CP SUFFIX** CASE 567CS

**CP SUFFIX** CASE 567BB

**CP SUFFIX** CASE 567BG

#### MARKING DIAGRAM

L M■		L30 M <b>■</b>		L308 M <b>■</b>
•		•		-
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CSP-4 CSP-6

I xxx

CSP-10

= Specific Device Code = Date Code = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

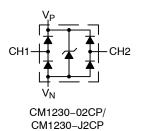
Device	Package	Shipping <sup>†</sup>
CM1230-02CP (Note 1)	CSP-4 (Pb-Free)	3,500/Tape & Reel
CM1230-J2CP (Note 1)	CSP-4 (Pb-Free)	3,500/Tape & Reel
CM1230-04CP	CSP-6 (Pb-Free)	3,500/Tape & Reel
CM1230-08CP	CSP-10 (Pb-Free)	3,500/Tape & Reel

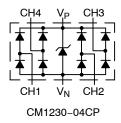
- †For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.
- \*Standard test condition is IEC61000-4-2 level 4 test circuit with each  $(A_{OUT}/B_{OUT})$  pin subjected to ±12 kV contact discharge for 1000 pulses. Discharges are timed at 1 second intervals and all 1000 strikes are completed in one continuous test run.
- 1. CM1230-02CP and CM1230-J2CP are the same mechanical package. Only difference is the Pin 1 orientation ('+' mark) on the tape and reel.

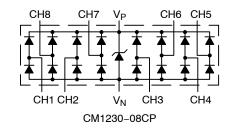
Handheld PCs/PDAs

CM1230/D

# **ELECTRICAL SCHEMATIC**







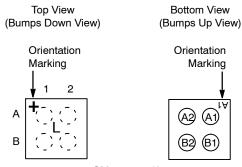
**Table 1. PIN DESCRIPTIONS** 

	2-Channel, 4-Bump CSP			
Pin	Name	Type	Description	
A1	V <sub>N</sub>	GND	Negative Voltage Supply Rail	
B1	CH2	I/O	ESD Channel	
A2	CH1	I/O	ESD Channel	
B2	V <sub>P</sub>	PWR	Positive Voltage Supply Rail	

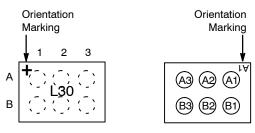
	4-Channel, 6-Bump CSP			
Pin	Name	Туре	Description	
A1	CH1	I/O	ESD Channel	
B1	CH2	I/O	ESD Channel	
A2	V <sub>P</sub>	PWR	Positive Voltage Supply Rail	
B2	V <sub>N</sub>	GND	Negative Voltage Supply Rail	
АЗ	СНЗ	I/O	ESD Channel	
В3	CH4	I/O	ESD Channel	

	8-Channel, 10-Bump CSP				
Pin	Name	Туре	Description		
A1	CH1	I/O	ESD Channel		
B1	CH2	I/O	ESD Channel		
A2	СНЗ	I/O	ESD Channel		
B2	CH4	I/O	ESD Channel		
АЗ	V <sub>P</sub>	PWR	Positive Voltage Supply Rail		
ВЗ	V <sub>N</sub>	GND	Negative Voltage Supply Rail		
A4	CH5	I/O	ESD Channel		
B4	CH6	I/O	ESD Channel		
A5	CH7	I/O	ESD Channel		
B5	CH8	I/O	ESD Channel		

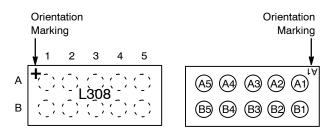
# **PACKAGE / PINOUT DIAGRAMS**



CM1230-02/J2 4-bump CSP Package



CM1230-04 6-bump CSP Package



CM1230-08 10-bump CSP Package

#### **SPECIFICATIONS**

#### **Table 2. ABSOLUTE MAXIMUM RATINGS**

Parameter	Rating	Units
Operating Supply Voltage (V <sub>P</sub> - V <sub>N</sub> )	6.0	V
Operating Temperature Range	-40 to +85	°C
Storage Temperature Range	−65 to +150	°C
DC Voltage at any Channel Input	$(V_N - 0.5)$ to $(V_P + 0.5)$	V

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

## **Table 3. STANDARD OPERATING CONDITIONS**

Parameter	Rating	Units
Operating Temperature Range	-40 to +85	°C

# Table 4. ELECTRICAL OPERATING CHARACTERISTICS (Note2)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
V <sub>P</sub>	Operating Supply Voltage (V <sub>P</sub> -V <sub>N</sub> )			3.3	5.5	V
Ι <sub>P</sub>	Operating Supply Current	(V <sub>P</sub> -V <sub>N</sub> ) = 3.3 V			8.0	μΑ
V <sub>F</sub>	Diode Forward Voltage Top Diode Bottom Diode	I <sub>F</sub> = 8 mA; T <sub>A</sub> = 25°C	0.60 0.60	0.80 0.80	0.95 0.95	V
I <sub>LEAK</sub>	Channel Leakage Current	$T_A = 25^{\circ}C; V_P = 5 \text{ V}, V_N = 0 \text{ V}, V_{IN} = 0 \text{ V to 5 V}$		±0.1	±1.0	μΑ
C <sub>IN</sub>	Channel Input Capacitance	At 1 MHz, V <sub>P</sub> = 3.3 V, V <sub>N</sub> = 0 V, V <sub>IN</sub> = 1.65 V		0.80	1.2	pF
$\Delta C_{IN}$	Channel Input Capacitance Matching	At 1 MHz, V <sub>P</sub> = 3.3 V, V <sub>N</sub> = 0 V, V <sub>IN</sub> = 1.65 V		0.02		pF
C <sub>MUTUAL</sub>	Mutual Capacitance between signal pin and adjacent signal pin	At 1 MHz, V <sub>P</sub> = 3.3 V, V <sub>N</sub> = 0 V, V <sub>IN</sub> = 1.65 V		0.15		pF
V <sub>ESD</sub>	In-system ESD Protection Peak Discharge Voltage at any channel input, in system a) Contact discharge per IEC 61000-4-2 standard b) Human Body Model, MIL-STD-883, Method 3015	T <sub>A</sub> = 25°C (Notes 4 and 5) T <sub>A</sub> = 25°C (Notes 3 and 5)	±8 ±15			kV
V <sub>CL</sub>	Channel Clamp Voltage Positive Transients Negative Transients	$T_A = 25^{\circ}\text{C}$ , $I_{PP} = 1\text{A}$ , $t_P = 8/20~\mu\text{S}$ (Note 5)		+9.8 -1.8		V
R <sub>DYN</sub>	Dynamic Resistance Positive Transients Negative Transients	I <sub>PP</sub> = 1 A, t <sub>P</sub> = 8/20 μS Any I/O pin to Ground (Note 5)		0.76 0.56		Ω

- 2. All parameters specified at  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$  unless otherwise noted.
  3. Human Body Model per MIL–STD–883, Method 3015,  $C_{Discharge} = 100$  pF,  $R_{Discharge} = 1.5$  K $\Omega$ ,  $V_P = 3.3$  V,  $V_N$  grounded.
  4. Standard IEC 61000–4–2 with  $C_{Discharge} = 150$  pF,  $R_{Discharge} = 330$   $\Omega$ ,  $V_P = 3.3$  V,  $V_N$  grounded.
  5. These measurements performed with no external capacitor on  $V_P$ .

- 6. Measured under pulsed conditions, pulse width = 0.7 ms, maximum current = 1.5 A.

## **PERFORMANCE INFORMATION**

# **Input Channel Capacitance Performance Curves**

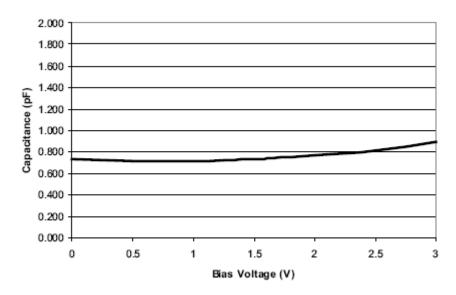


Figure 1. Typical Variation of C $_{IN}$  vs.  $V_{IN}$  (f = 1 MHz,  $V_P$  = 3.3 V,  $V_N$  = 0 V, 0.1  $\mu F$  chip capacitor between  $V_P$  and  $V_N$ ,  $T_A$  = 25°C)

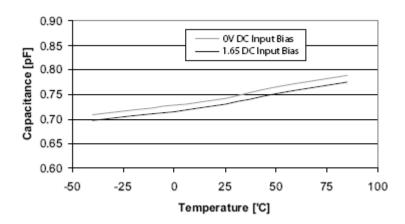


Figure 2. Typical Variation of  $C_{IN}$  vs. Temp (f = 1 MHz,  $V_{IN}$  = 30 mV,  $V_P$  = 3.3 V,  $V_N$  = 0 V, 0.1  $\mu F$  chip capacitor between  $V_P$  and  $V_N$ )

# PERFORMANCE INFORMATION (Cont'd)

Typical Filter Performance (nominal conditions unless specified otherwise, 50  $\Omega$  Environment)

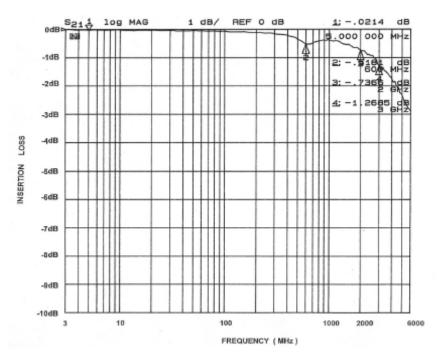


Figure 3. Insertion Loss vs. Frequency (0 V DC Bias,  $V_P = 3.3 \text{ V}$ )

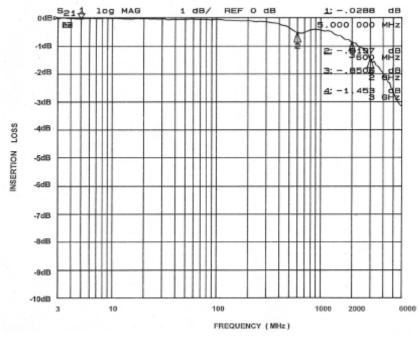


Figure 4. Insertion Loss vs. Frequency (2.5 V DC Bias,  $V_P = 3.3 \text{ V}$ )

# **APPLICATION INFORMATION**

**Table 5. PRINTED CIRCUIT BOARD RECOMMENDATIONS** 

Parameter	Value
Pad Size on PCB	0.275 mm
Pad Shape	Round
Pad Definition	Non-Solder Mask defined pads
Solder Mask Opening	0.325 mm Round
Solder Stencil Thickness	0.125 – 0.150 mm
Solder Stencil Aperture Opening (laser cut, 5% tapered walls)	0.330 mm Round
Solder Flux Ratio	50/50 by volume
Solder Paste Type	No Clean
Pad Protective Finish	OSP (Entek Cu Plus 106A)
Tolerance – Edge To Corner Ball	±50 μm
Solder Ball Side Coplanarity	±20 μm
Maximum Dwell Time Above Liquidous	60 seconds
Maximum Soldering Temperature for Lead-free Devices using a Lead-free Solder Paste	260°C

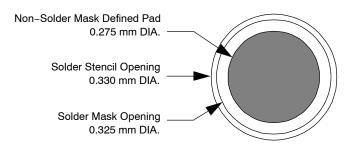


Figure 5. Recommended Non-Solder Mask Defined Pad Illustration

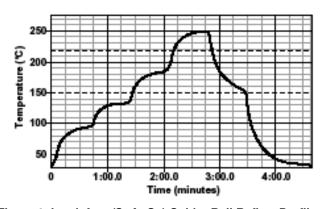
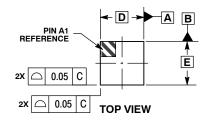


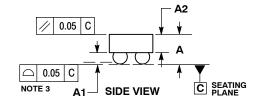
Figure 6. Lead-free (SnAgCu) Solder Ball Reflow Profile

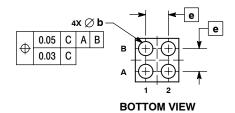
## PACKAGE DIMENSIONS

## WLCSP4, 0.96x0.96

CASE 567CS ISSUE O





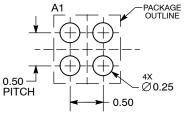


#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.61	0.69	
A1	0.21	0.28	
A2	0.41 REF		
b	0.29	0.34	
D	0.96 BSC		
E	0.96 BSC		
e	0.50 BSC		

#### **RECOMMENDED SOLDERING FOOTPRINT\***

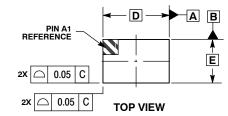


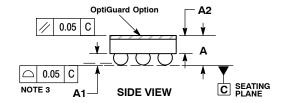
DIMENSIONS: MILLIMETERS

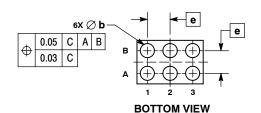
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## WLCSP6, 1.46x0.96 CASE 567BB

**ISSUE O** 







# NOTES:

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- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

  2. CONTROLLING DIMENSION: MILLIMETERS.

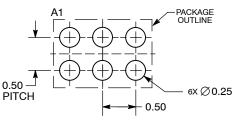
  3. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS.

•	ONOWING OF GOLDLIND			
		MILLIMETERS		
	DIM	MIN	MAX	
	Α	0.56	0.72	
	A1	0.21	0.27	
	A2	0.42 REF		
	b	0.29	0.35	

1.46 BSC

0.96 BSC

#### **RECOMMENDED SOLDERING FOOTPRINT\***



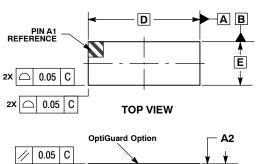
DIMENSIONS: MILLIMETERS

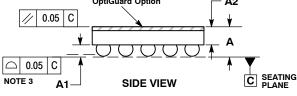
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

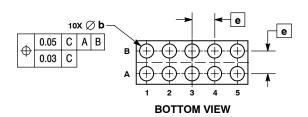
## PACKAGE DIMENSIONS

# WLCSP10, 2.46x0.96

CASE 567BG **ISSUE 0** 





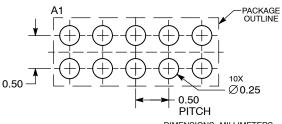


#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASMF Y14 5M 1994
- CONTROLLING DIMENSION: MILLIMETERS. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.56	0.72	
A1	0.21	0.27	
A2	0.42 REF		
b	0.29	0.35	
D	2.46 BSC		
Е	0.96 BSC		
е	0.50	BSC	

#### **RECOMMENDED SOLDERING FOOTPRINT\***



DIMENSIONS: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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